

Test the Flexibility of Substrates and Signal Cables

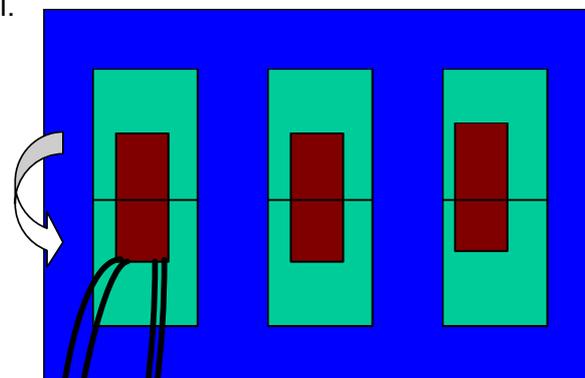
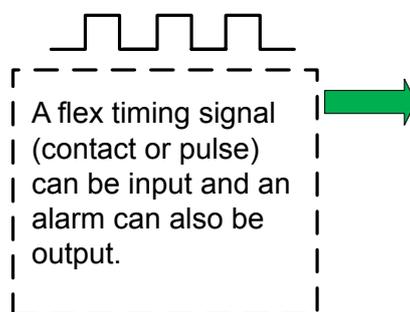
Record and monitor the chronological changes in the resistance values in a flex test of flexible substrates and signal cables.

■ Highlights

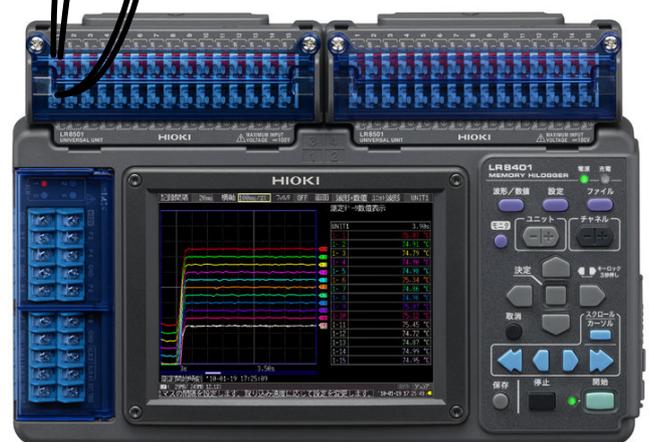
- Resistance changes caused by the flex stress on the flexible wiring substrate used in the wiring to moving parts such as wiring that passes through the hinge of a folding mobile phone or wiring in a camera lens can be recorded on multiple channels.
- The LR8401-20 Memory HiLogger provides 30 channels as standard for 4-terminal measurements and can perform measurements on up to 60 channels if channels are added.
- Changes in the temperature during measurement can also be recorded simultaneously by measuring the temperature on another unused channel.
- An increase in the resistance value and number of flexes for a broken wire can also be measured by counting the number of flexes using the integration function of pulse digital inputs. Furthermore, the signal at that point can also be output using the alarm output terminal.

To measure resistance, 4-terminal measurements can be performed in the 10 Ω range (at a resolution of 0.5 m Ω) to 200 Ω range (at a resolution of 10 m Ω) by applying a current of 1 mA.

Up to 10 ms high-speed sampling (on 15 channels)
20 ms on 15 to 30 channels
50 ms more than 31 channels



(Flex testing machine)



LR8401-20

(Datalogger with Voltage/Thermocouple/Pt100 input unit)

Products used

- MEMORY HILOGGER LR8401-20

Expanded option

- UNIVERSAL UNIT (15ch) LR8501